30900601-Consulting 09-version1.0

# Test procedures for Sampled Values Publishers according to the "Implementation Guideline for Digital Interface to Instrument Transformers using IEC 61850-9-2"

Version 1.1

On request of UCAIUG

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#### 1 INTRODUCTION

The scope of the test is an IED publishing IEC 61850-9-2 sampled value messages constrained by the 9-2LE guideline. For example such IED could be a merging unit. A merging unit is a physical device that converts input signals from (non) conventional CT's and/or VT's and merges the signals into a digital IEC 61850-9-2 sampled value message.

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The test procedures in this document are based on the "Implementation Guideline for Digital Interface to Instrument Transformers using IEC 61850-9-2, version 2.1, July 2004" further referred to as 9-2LE.

Note: In case a 9-2 publishing IED supports GOOSE or MMS based services to transfer binary status or control indications the applicable server conformance test procedures version 2.2 have to be used for the test

#### 1.1 Glossary

DUT	Device Under Test
ICD	IED configuration description in SCL-format
IED	Intelligent Electronic Device
MICS	Model Implementation Conformance Statement
MU	Merging Unit
PICS	Protocol Implementation Conformance Statement
TICS	Technical Issues Implementation Conformance Statement
PIXIT	Protocol Implementation eXtra Information for Testing
PPS	Pulse Per Second
SCD	Substation configuration description in SCL-format
SCL	Substation Configuration Language
TISSUE	Technical issue
UCA IUG	UCA International Users Group

## 1.2 Identifications

The following table gives the exact identification of tested equipment and test environment used for this conformance test.

DUT	<identification and="" device="" name="" of="" short="" test,="" th="" the="" type,<="" under=""></identification>
	hardware / software version>
	Supported sampling rates: 80 and/or 256 samples per cycle
	Supported frequencies: 50Hz and/or 60Hz
MANUFACTURER	<name, dut="" location="" manufacturer="" of="" the=""></name,>
PICS	<complete description="" of="" pics="" reference="" the=""></complete>
MICS	<complete description="" mics="" of="" reference="" the=""> OR</complete>
	reference to 9-2LE
TICS	<complete description="" of="" reference="" the="" tics=""> OR</complete>
	reference to 9-2LE
PIXIT	<complete description="" of="" pixit="" reference="" the=""></complete>
ICD or SCD	<complete configuration="" description="" file="" of="" reference="" scl="" the=""></complete>
TEST INITIATOR	MANUFACTURER
TEST FACILITY	<name address="" and="" facility="" of="" test=""></name>
TEST ENGINEER	<name address="" and="" e-mail="" engineer="" of="" test=""></name>
TEST SESSION	<date and="" location="" of="" session="" test="" the=""></date>
ANALYSER	<name analyzer(s),="" and="" type="" version="" x.y=""></name>
SIGNAL GENERATOR	<name and="" equipment="" simulator="" type=""></name>
PPS TIME MASTER	<name and="" master="" of="" time="" type=""></name>
MEDIA CONVERTERS	<name and="" converters="" media="" of="" type=""></name>

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#### 2 **TEST ENVIRONMENT**

The test environment consists of the following components:

- DUT = 9-2LE publisher
- Current and/or Voltage signal generator
- 9-2LE Analyzer
- PPS time master

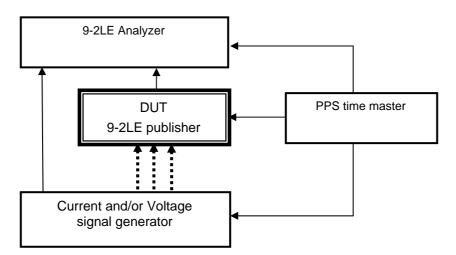


Figure 2.1 The test environment

The analyser can compare the "reference" sampled values from the signal generator with the sampled values from the DUT. The signal generator shall be accurate enough to perform the accuracy plausibility tests.

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## 3 TEST RESULTS

Table 3.1 in this Chapter gives an overview of the conformance test results. References shown in the table columns refer to references of individual test procedures in clause 5.

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The **Mandatory** column indicates the mandatory test cases with test result passed and the **Conditional** column indicates the conditional test cases with test result passed.

The **Verdict** column indicates the test result of all applicable test procedures in the test group. When one or more test procedures have test result Failed the test group receives verdict Failed.

Test Group	Mandatory	Conditional	Verdict
Documentation			
Configuration			
11a Sampled Value			
Publishing			

Table 3.1 Overview of applicable test cases for *DUT* 

#### 4 CONCLUSION AND RECOMMENDATIONS

Based on the test results described in this report, TEST FACILITY declares the tested IEC 61850 implementation in the DUT has **[not shown/shown] to be non-conforming** to 9-2LE as specified in the PICS, MICS, PIXIT, TICS and ICD and configured according to the SCD.

#### 4.1 **Recommendations following from the test**

The following comments and recommendations apply for the *DUT*:

<comments and recommendation from test facility>

## 5 TEST PROCEDURES FOR 9-2LE PUBLISHERS

#### 5.1 **Documentation**

ld	Test procedure	Verdict
Doc1	Check if the manufacturer documentation and hardware / software versions of the DUT do match: a) PICS b) MICS (reference to 9-2LE) c) PIXIT d) TICS (reference to 9-2LE) e) Hardware/software versions match	<ul> <li>Passed</li> <li>Failed</li> <li>Inconclusive</li> </ul>
Doc2	Verify the PIXIT matches the PIXIT template from the test procedures document	<ul> <li>□ Passed</li> <li>□ Failed</li> <li>□ Inconclusive</li> </ul>

# 5.2 **Configuration**

Id	Test procedure	Verdict
Cnf1	Test if the ICD configuration file conforms to the SCL schema (IEC 61850-6)	□ Passed □ Failed
		□ Inconclusive
Cnf2	Check if the SCL configuration file corresponds with the actual	□ Passed
	names, data-sets, and values exposed by the DUT on the	□ Failed
	network.	□ Inconclusive
	For ICD: MsvID = xxxxMUnn01 or xxxxMUnn02, ConfRev=1, APPID = 0x4000	
	For SCD: MsvID and all SV communication parameters	
Cnf3	Check if the server "SMVSettings" capabilities in the ICD	□ Passed
	"services" section do match with the IED capabilities	□ Failed
		Inconclusive
Cnf4	Verify the name and logical nodes (LLN0, LPHD, InnATCTR1,	□ Passed
	InnBTCTR2, InnCTCTR3, InnNTCTR4, UnnATVTR1,	□ Failed
	UnnBTVTR2, UnnCTVTR3, UnnNTVTR4) of the logical device "xxxxMUnn" (9-2LE table 4) in the SCL	□ Inconclusive

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Id	Test procedure	Verdict
Cnf5	Verify the logical node LLN0 of the logical device xxxxMUnn (9- 2LE table 5) in the SCL: - dataset "PhsMeas1" - sampled value control block "MSVCB01"or "MSVCB02"	<ul> <li>Passed</li> <li>Failed</li> <li>Inconclusive</li> </ul>
Cnf6	Verify the dataset PhsMeas1 (9-2LE table 6) in the SCL	Passed     Failed     Inconclusive
Cnf7	Verify the common data class SAV and scale factor values (9-2LE table 7) in the SCL: 0.001 for current; 0.01 for voltage	Passed     Failed     Inconclusive
Cnf8	Verify the Multicast sampled value control block "MSVCB01" and/or "MSVCB02" (9-2LE table 8 and table 9) in the SCL	Passed     Failed     Inconclusive
Cnf9	Verify that if the device does not supply all samples, 'dummy' SAV data objects might be referenced in the data set. To detect the difference between dummy and real samples in the SCL, the ICD shall have all LN's included but the ones that are not supported have the LN Mode preconfigured to "Off".	<ul> <li>Passed</li> <li>Failed</li> <li>Inconclusive</li> <li>Not applicable</li> </ul>

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#### 5.3 **Communication services**

#### 5.3.1 Abstract test cases

Test ID	Test Case	M/C	
Svp1	Verify that the maximum delay time from taking the sample to sending the corresponding message is within the limit specified in IEC 60044-8 clause 5.3.2 Note 2: 3 ms (+10 $\%$ / -100 $\%$ )		
Svp2	Verify that physical layer is 100Base-FX full duplex with ST or MT-RJ connectors or 100Base-TX with RJ45 connector		
Svp3	Verify that the format of the link layer matches with 9-2LE Annex A figure 3	М	
Svp4	Verify that application layer matches with MSVCB01: APDU with 1 ASDU (9-2LE Annex A figure 4)	C1	
Svp5	Verify that application layer matches with MSVCB02: APDU with 8 ASDU (9-2LE Annex A figure 4)	C1	
Svp6	Verify the format of the ASDU matches with 9-2LE Annex A figure 5	М	
Svp7	Verify that the calculated neutral samples have the derived quality bit set	C2	
Svp8	Verify that the MSVCB01 samples are transmitted with 80 messages per cycle	C1	
Svp9	Verify that the MSVCB02 samples are transmitted with 32 (256/8) messages per cycle	C1	
Svp10	Verify that SmpCnt will be incremented each time a new sampling value is taken. The counter shall be set to zero if the sampling is synchronised by clock signal (SmpSynch = TRUE) and the synchronising signal occurs. The value zero shall be given to the data set where the sampling of the primary current coincides with the sync pulse.	М	
Svp11	Verify that the sampled values match with the analog signals	М	
Svp12	Verify that the voltage scaling parameters are configured as specified in the PIXIT and correctly applied	C3	
Svp13	Verify that the current scaling parameters are configured as specified in the PIXIT and correctly applied	C3	
Svp14	Verify that the DUT is synchronised with PPS signal. Verify that in case the PPS signal is lost the SmpSynch in the SV message shall be set to FALSE. "SmpCnt" shall wrap as if a synchronization pulse would be present	М	
Svp15	Verify that after restoring the power the DUT shall publish valid 9-2 messages within specified time (PIXIT).	М	
Svp16	Verify that in TEST mode the quality bit TEST is set for each sample (PIXIT)	C4	
Svp17	Signals that are not measured or calculated shall have the corresponding Quality bit = Invalid	C5	

#### Conditions

C1 = at least 80 or 256 sample rate shall be supported

C2 = mandatory in case neutral values are calculated

C3 = mandatory in case the DUT is connected to a conventional CT/VT

C4 = mandatory in case TEST mode is supported

C5 = mandatory in case DUT does measure less then 3 currents and 3 voltages or the DUT supports Quality = Invalid

#### 5.3.2 Detailed test procedures

Svp1	-	t the maximum delay time from taking the sample to ne corresponding message is within the limit	<ul> <li>□ Passed</li> <li>□ Failed</li> <li>□ Inconclusive</li> </ul>		
9-2LE clause 5					
IEC 60044-8 cla	use 5.3.2 n	ote 2 <sup>1</sup>			
PIXIT					
Expected result					
2. DUT sample	s the signa	als as configured			
3. DUT sends s	sampled va	alue messages. The measured delay time shall be	less than 3 ms		
(+10% / -10	00%). The	measured delay time is defined as the fraction of s	second of the		
capture time	e of the me	essage with SmpCnt=0			
4. Maximum de	lay does r	ot exceed value specified in PIXIT			
Test description					
1. Configure the	ne DUT wit	th the correct parameters			
2. Generate 5	2. Generate 50 Hz current and/or voltage signals				
3. Capture the	sampled	values messages for 1 minute			
4. Repeat step	1 to 3 five	e times			
5. Repeat step	5. Repeat step 1 to 4 for 60 Hz and other sampling rates				
Comment					
Note: the test ca	se is passe	ed when the measured delay time is below the specified	l limit.		
The measured delays are:					
- 50 Hz and 80 s	- 50 Hz and 80 samples =				
- 50 Hz and 256	- 50 Hz and 256 samples =				
- 60 Hz and 80 s	- 60 Hz and 80 samples =				
- 60 Hz and 256	- 60 Hz and 256 samples =				
-					

<sup>&</sup>lt;sup>1</sup> IEC 60044-8 clause 5.3.2: NOTE 2 If the merging unit is intended to be used with synchronization pulses, the rated delay time is 3 ms (+10 % – 100 %) for all data rates, since it is not relevant for phase error.

Svp2	Verify that physical layer is 100Base-FX full duplex with ST or MT-RJ connectors or 100Base-TX with RJ45 connector	<ul> <li>Passed</li> <li>Failed</li> <li>Inconclusive</li> </ul>					
9-2LE clause 6.2	9-2LE clause 6.2.1						
Expected result							
3. DUT sends s	sampled value messages on the configured connector						
6. DUT sends s	sampled value messages on the configured connector						
Test description							
1. Configure the	ne DUT using the copper connection						
2. Generate cu	2. Generate current and/or voltage signals						
3. Capture the sampled values messages for 1 minute							
4. Configure th	4. Configure the DUT using the fiber connection						
5. Generate cu	5. Generate current and/or voltage signals						
6. Capture the sampled values messages for 1 minute							
<u>Comment</u>	Comment						
DUT has 100Base-FX full duplex with ST / MT-RJ connectors and/or 100Base-TX with a RJ45							
connector	connector						

Svp3	Verify the format of the link layer	<ul><li>Passed</li><li>Failed</li><li>Inconclusive</li></ul>				
9-2LE Annex A	igure 3, clause 6.2.2					
Expected result						
3. DUT sends s	sampled value messages with the following format of the lin	k layer:				
- destination	n MAC address = 01-0C-CD-04-xx-xx					
- TPID	= 0x8100					
- VLAN prio	rity as configured (default = 4)					
- VLAN ID a	- VLAN ID as configured (default = 0x000)					
- Ethertype	- Ethertype = 0x88BA					
- APPID	= 0x4000					
- reserved 1	= 0x0000					
- reserved 2	$2 = 0 \times 0000$					
Test description						
1. Configure the	1. Configure the DUT					
2. Generate c	2. Generate current and/or voltage signals					
3. Capture the sampled values messages for 1 minute						
Comment						

		□ Passed		
Svp4	Verify that application layer matches with MSVCB01: APDU	□ Failed		
	with 1 ASDU	□ Inconclusive		
9-2LE Annex A	figure 4, clause 7.1.4			
Expected result				
3. DUT sends s	sampled value messages with 1 ASDU			
- noAsdu =	1			
- svID = xxx	xMUnn01			
- smpCount	= 03999 (50Hz) or 04799 (60Hz)			
- confRev =	- confRev = 1			
<ul> <li>smpSynch = TRUE in case PPS is connected</li> </ul>				
- sequence of data				
- refresh tim	- refresh time and sample rate are not present			
Test description				
1. Configure the	1. Configure the DUT			
2. Generate cu	2. Generate current and/or voltage signals			
3. Capture the sampled values messages for 1 minute				
Comment	Comment			

Svp5	Verify that application layer matches with MSVCB02: APDU with 8 ASDU	<ul> <li>Passed</li> <li>Failed</li> <li>Inconclusive</li> </ul>
9-2LE Annex A	figure 4, clause 7.1.4	
- noAsdu = - svID = xxx - smpCount - confRev = - smpSynch - sequence	xXMUnn02 = 012799 (50Hz) or 0 15359 (60Hz) 1 = TRUE in case PPS is connected	
3. Capture the		

Svp6	Verify the format of the ASDU dataset	<ul> <li>Passed</li> <li>Failed</li> <li>Inconclusive</li> </ul>	
9-2LE Annex A f	igure 5		
<ul> <li><u>Expected result</u></li> <li>3. DUT sends sampled value messages with the correct format of the ASDUs         <ul> <li>4 phase Currents</li> <li>4 phase Voltages</li> <li>Not supported values are 0 and have the corresponding invalid quality bit set</li> </ul> </li> </ul>			
Test description			
<ol> <li>Configure the DUT with the correct sample rate</li> <li>Generate current and/or voltage signals</li> </ol>			
<ol> <li>Capture the sampled values messages for 1 minute</li> </ol>			
Comment			

		□ Passed	
Svp7	Verify that the calculated neutral samples have the derived	□ Failed	
	quality bit set	□ Inconclusive	
9-2LE clause 6.2	2.3		
Expected result			
3. DUT sends s	sampled value messages with the correct format of the ASDL	Js	
- Calculated	neutral values have the derived quality bit (0x2000) set		
Test description			
1. Configure the DUT with the correct sample rate			
2. Generate current and/or voltage signals			
3. Capture the sampled values messages for 1 minute			
Comment	Comment		

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Svp8	Verify that the MSVCB01 samples are transmitted with 80 messages per cycle	<ul> <li>Passed</li> <li>Failed</li> <li>Inconclusive</li> </ul>		
9-2LE clause 7.2	1.4			
Expected result				
2. DUT sample	s the signals as configured			
	<ol> <li>In one minute DUT sends 240000±1 sampled value messages for 50 Hz and 288000±1 messages for 60 Hz.</li> </ol>			
Test description				
1. Configure th	ne DUT with the correct parameters			
2. Generate 50	) Hz current and/or voltage signals			
3. Capture the	3. Capture the sampled values messages for 1 minute			
4. Repeat step	4. Repeat step 1 to 3 five times			
5. Repeat step 1 to 4 for 60 Hz				
Comment				

Svp9	Verify that the MSVCB02 samples are transmitted with 32 (256/8) messages per cycle	<ul><li>Passed</li><li>Failed</li><li>Inconclusive</li></ul>		
9-2LE clause 7.	1.4			
Expected result				
2. DUT sample	s the signals as configured			
3. In one minut 60 Hz.	3. In one minute DUT sends 96000±1 sampled value messages for 50 Hz and 115200±1 for 60 Hz.			
Test description				
1. Configure the	ne DUT with the correct parameters			
2. Generate 5	0 Hz current and/or voltage signals			
3. Capture the	sampled values messages for 1 minute			
4. Repeat step	4. Repeat step 1 to 3 five times			
5. Repeat step 1 to 4 for 60 Hz				
<u>Comment</u>				

Svp10	Verify that SmpCnt will be incremented and reset	□ Passed □ Failed	
• · p · •			
		□ Inconclusive	
9-2LE clause 7.2	2.1		
Expected result			
3. DUT sends s	sampled value messages.		
- SmpCnt	is incremented at each sample (ASDU)		
- SmpCnt	value zero shall be given to the data set where the sampling	of the primary	
current	coincides with the sync pulse (plausibility check)		
	ng unit does not receive a synchronization signal SmpCnt sha ation pulse would be present.	all wrap as if a	
Test description			
1. Configure the	ne DUT with the correct parameters		
2. Generate 5	2. Generate 50 Hz current and/or voltage signals		
3. Capture the	3. Capture the sampled values messages for 1 minute		
4. Disconnect	4. Disconnect the PPS		
5. Capture the	5. Capture the sampled values messages for 1 minute		
-	6. Repeat step 1 to 5 for 60 Hz		
, , ,			
Comment			
The SmpCnt zer	ro at synch pulse is a plausibility check not an accuracy test.		

		□ Passed
Svp11	Verify that the sampled values match with the analog signals	□ Failed
		□ Inconclusive
9-2LE Annex C	and Annex D	
Expected result		
3. Voltages		
	calculated, check that VN is equal to VA, VB, VC when apply	ing 1 phase
voltage		
- When a zero	pplying a symmetrical 3 phase voltage system the calculated	VN is close to
	oplying the same voltage to VA, VB, VC, the magnitude and p	olarity are the
	nd VN is 3 times the magnitude of a phase voltage	
Currents		
	alculated, check that IN is equal to IA, IB, IC when applying	1 phase current
	oplying a symmetrical 3 phase current system the calculated	
zero		
- When a	pplying "line-to-line" current, the magnitude is the same and t	he polarity has
the oppo	osite value, IN is close to zero	
Test description		
1. Configure the	ne DUT with the correct parameters 50 Hz	
2. Generate th	e following 50 Hz current and/or voltage signals for 3 phase	signal
generator:		
	s symmetrical 3 phase	
	s per phase: A -> B -> C	
	phase test generator:	
	s inject same voltage to A, B and C	
	s inject "line-to-line" current into 2 phases A-B	
	s inject "line-to-line" current into 2 phases B-C	
	s inject "line-to-line" current into 2 phases C-A	
	s per phase: A -> B -> C	
-	sampled values messages 1 to 3 for 60 Hz	
4. Repeat step		
<u>Comment</u>		
	ility check not an accuracy test.	

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Svp12	Verify that the voltage scaling parameters are configured as specified in the PIXIT and correctly applied	<ul><li>Passed</li><li>Failed</li><li>Inconclusive</li></ul>	
9-2LE Annex C	and Annex D		
PIXIT			
Expected result			
3. Voltages			
- The magn	itude of sampled values for VA, VB, VC, (VN) match applied	voltage.	
- The config	ured scaling parameters (VT ratios) are correctly taken into a	account	
Test description			
-	ne DUT with the correct parameters 50 Hz		
2. Generate th	2. Generate the following 50 Hz voltage signals		
- 15 second	- 15 seconds all 3 phases		
- 15 second	- 15 seconds per phase: A -> B -> C		
3. Capture the	3. Capture the sampled values messages		
4. Repeat step	4. Repeat step 1 to 3 for 60 Hz		
Comment			
This is a plausibility check not an accuracy test.			

Svp13	Verify that the current scaling parameters are configured as specified in the PIXIT and correctly applied	<ul><li>Passed</li><li>Failed</li><li>Inconclusive</li></ul>
9-2LE Annex C a PIXIT	and Annex D	
-	itude of sampled values for IA, IB, IC, (IN) match applied cur jured scaling parameters (CT ratios) are correctly taken into a	
<ol> <li>Generate th</li> <li>15 second</li> <li>15 second</li> <li>3. Capture the</li> </ol>	ne DUT with the correct parameters 50 Hz e following 50 Hz current signals s all 3 phases s per phase: A -> B -> C 9-2 sampled values messages o 1 to 3 for 60 Hz	
<u>Comment</u> This is a plausib	ility check not an accuracy test.	

Svp14		Verify that the DUT is synchronised with PPS signal	<ul> <li>Passed</li> <li>Failed</li> <li>Inconclusive</li> </ul>
9-2LE clau	ise 7.2	2.1	
PIXIT			
Expected I	<u>esult</u>		
3. When	PPS	s connected DUT sends sampled value messages with Smp	Synch = TRUE.
When	PPS	s disconnected and when DUT has left the hold-over mode it	t sends
messa	ges v	/ith SmpSynch = FALSE	
Test descr	iption		
1. Config	1. Configure the DUT with the correct parameters		
2. Gener	<ol><li>Generate 50 Hz current and/or voltage signals</li></ol>		
3. Captur	3. Capture the sampled values messages, disconnect the PPS after 10 seconds and		
conne	connect it again after 1.5 times the specified holdover time		
4. Repea	4. Repeat step 1 to 3 for 60 Hz		
<u>Comment</u>			

Svp15	Verify that after restoring the power the DUT shall publish valid 9-2 messages within specified time (PIXIT).	<ul> <li>Passed</li> <li>Failed</li> <li>Inconclusive</li> </ul>	
9-2LE clause 7.2	2.1		
PIXIT			
Expected result			
3. DUT sends v	valid sampled value messages within the PIXIT specified time	e after restoring	
the power			
Test description			
1. Configure the DUT with the correct parameters			
2. Generate 50 Hz current and/or voltage signals, after 10 seconds disconnect and restore			
the power supply			
3. Capture the sampled values messages until valid samples are transmitted			
4. Repeat step 1 to 3 for 60 Hz			
Comment	Comment		

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Svp16	Verify that in TEST mode the quality bit TEST is set for	□ Passed		
		□ Failed		
	each sample (PIXIT)	□ Inconclusive		
9-2LE clause 7.2.1				
PIXIT				
Expected result				
3. DUT sends sampled value messages with quality bit TEST (0x0800) for each sample				
Test description				
1. Configure the DUT with the correct parameters and enable TEST mode				
2. Generate 50 Hz current and/or voltage signals				
3. Capture the sampled values messages for 1 minute				
4. Repeat step 1 to 3 for 60 Hz				
Comment				

Svp17	Signals that are not measured or calculated shall have the corresponding Quality bit = Invalid (PIXIT)	<ul> <li>Passed</li> <li>Failed</li> <li>Inconclusive</li> </ul>		
9-2LE clause 7.1.3				
PIXIT				
Expected result				
3. Signals that are not measured or calculated or as specified in the PIXIT shall have the				
corresponding Quality bit Invalid (0x0001)				
Test description				
1. Configure the DUT as specified in the PIXIT				
2. Generate 50 Hz current and/or voltage signals				
3. Capture the sampled values messages for 1 minute				
4. Repeat step 1 to 3 for 60 Hz				
Comment				

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## ANNEX A PIXIT FOR 9-2LE PUBLISHER

Description	Value / Clarification
Supported nominal frequencies	50 Hz Y/N
	60 Hz Y/N
Supported sampling rates	80 samples per cycle Y/N
	256 samples per cycle Y/N
9-2 connector type	ST, MT-RJ and/or RJ45
Support test mode	Y/N
Input voltage and currents signals	0, 1, 3 or 4 phase voltages
	0, 1, 3 or 4 phase currents
Are neutral sampled values calculated?	Y/N/Configurable
How are the CT/VT ratios configured	
(only applicable for MU connected to conventional CT/VT)	
At losing the PPS signal after how much	0 if there is no hold-over mode
time sets the MU 'SmpSynch' to false (hold over mode)	seconds
At restoring the PPS signal after how much time sets the MU 'SmpSynch' to true	seconds
Max length for IED name	Max length of MsvID = 32
What is the (rated) delay time between taking the sample and sending the corresponding SV message	microseconds
Which quality codes are supported	Derived Y/N
	Test Y/N
In which conditions is the quality field Validity set to the value Invalid	For example a MU without voltage inputs the voltage samples have quality invalid
What is the maximum startup time after a power supply interrupt	seconds
<additional items=""></additional>	

Revision history

Version	Changes
1.0, January 12, 2010	Initial approved version
1.1, May 18, 2010	Changes based upon application of first test